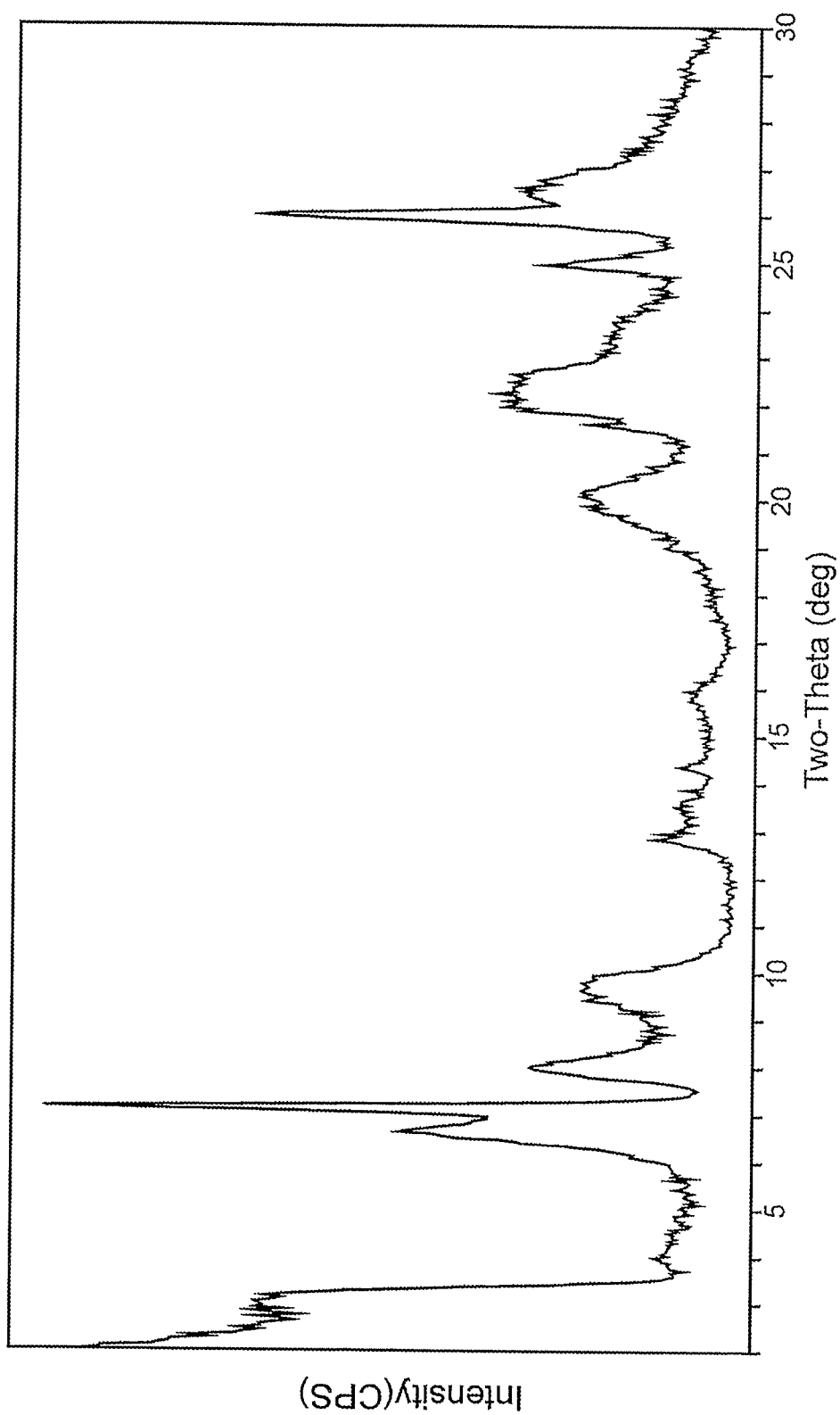
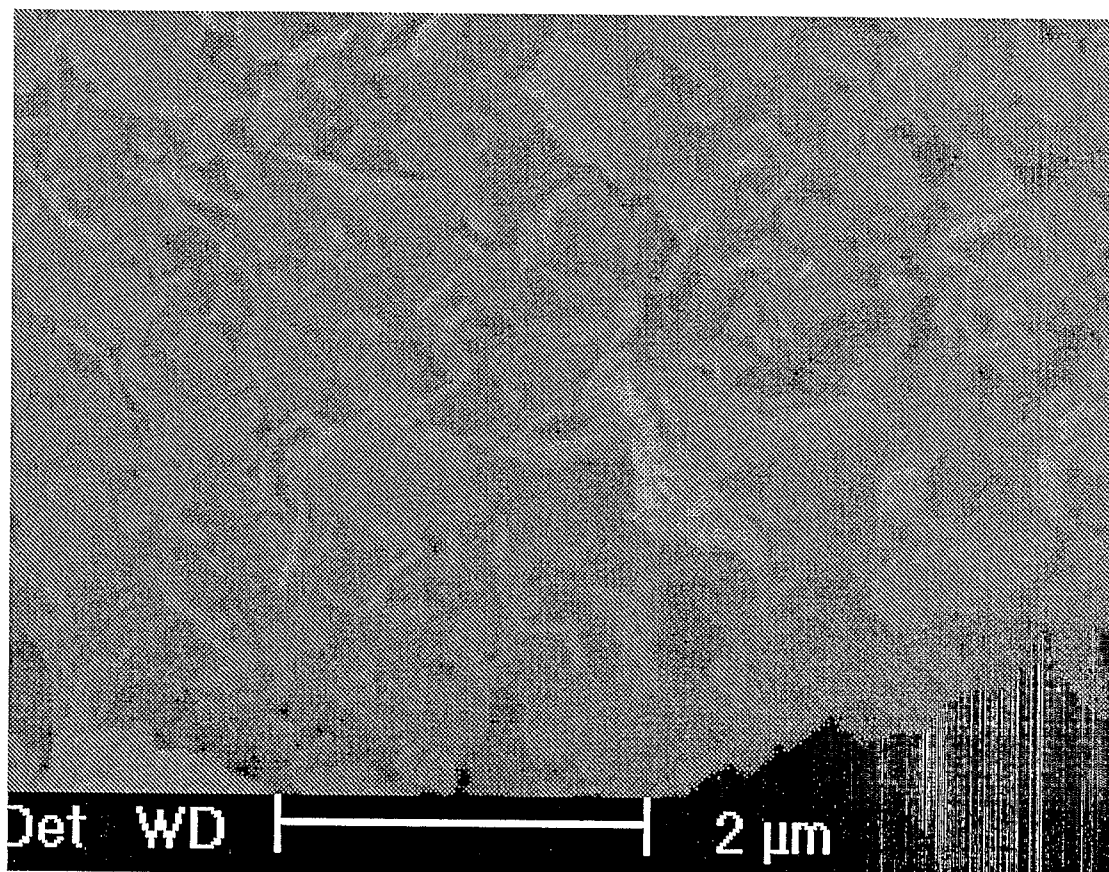


Figure 1
X-ray diffraction pattern of the material prepared according to Example A



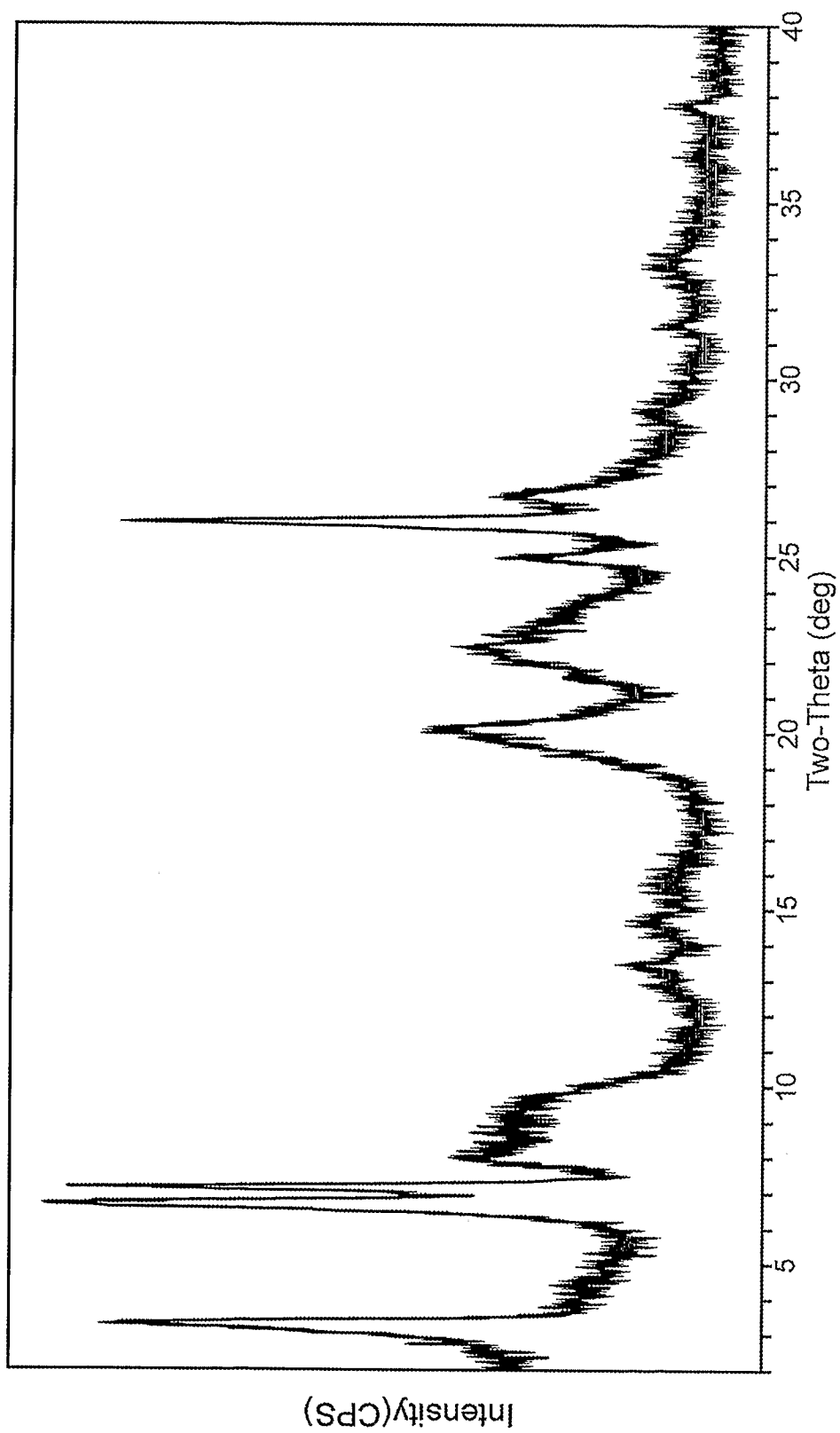
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Figure 2
SEM of the material prepared according to Example A



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Figure 3
X-ray diffraction pattern of the material prepared according to Example 1



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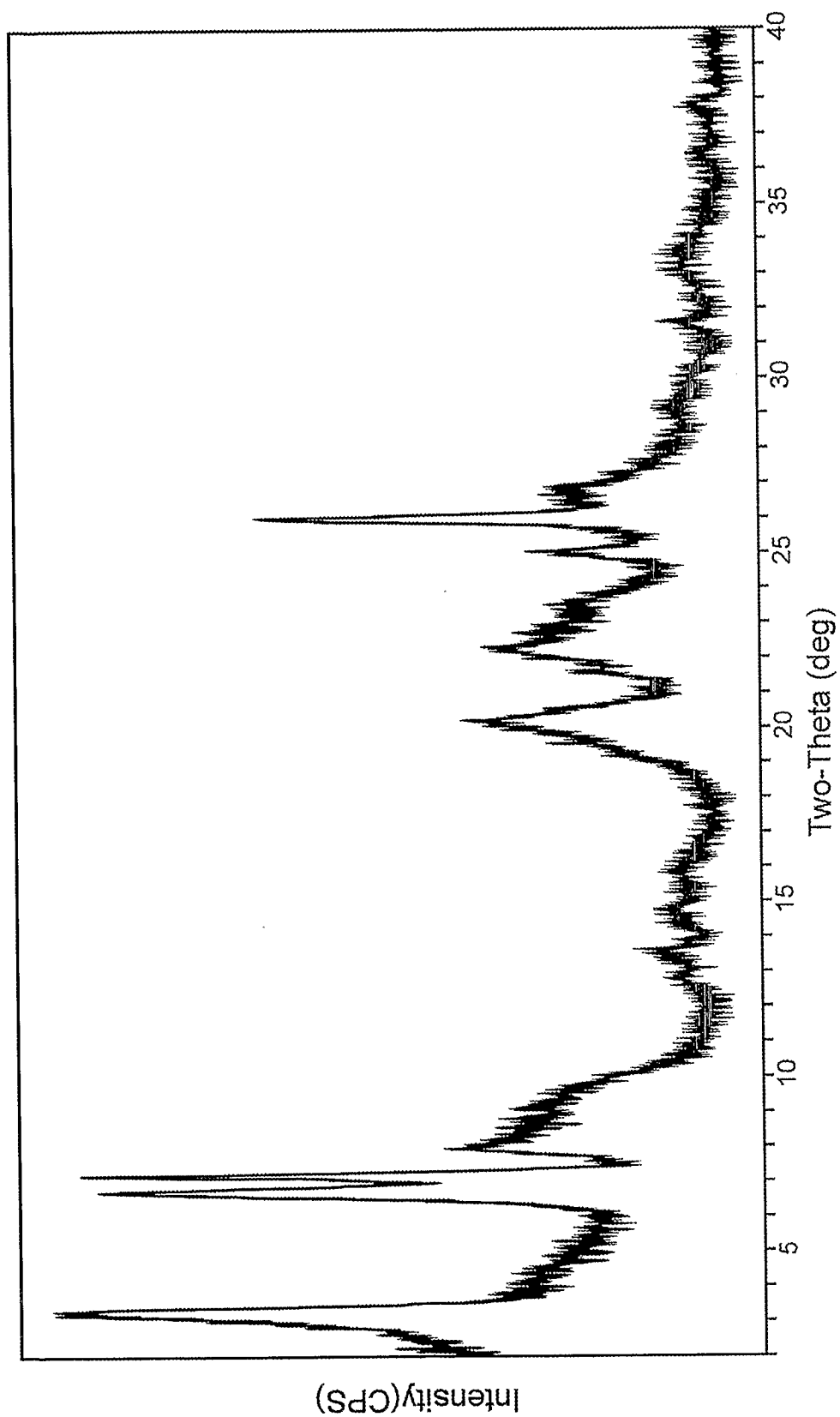
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Figure 4
SEM of the material prepared according to Example 1



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Figure 5
X-ray diffraction pattern of the material prepared according to Example 2



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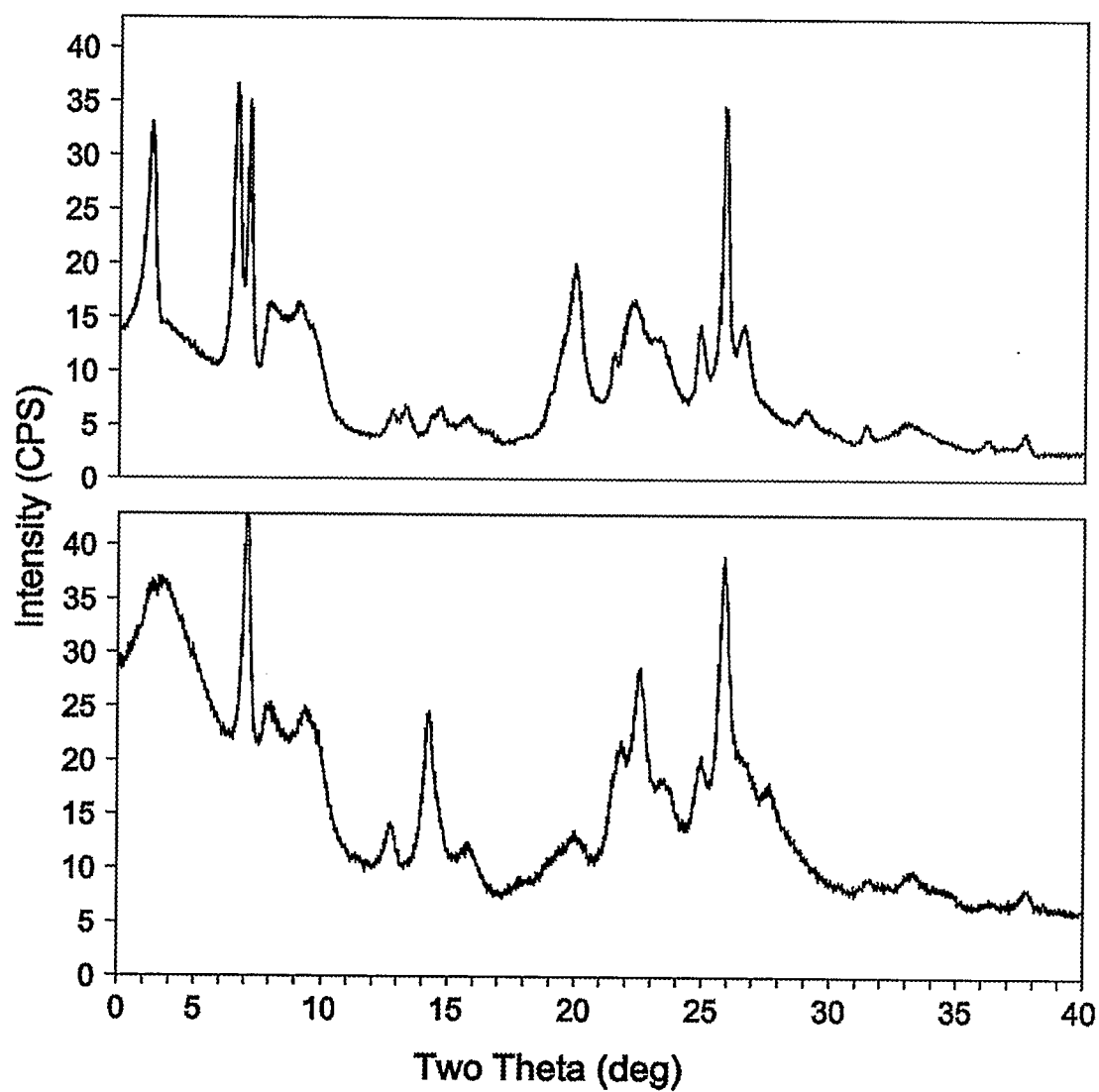
Figure 6
SEM of the material prepared according to Example 2



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Fig. 7

X-ray diffraction pattern of the materials prepared according to Example 5:
as-synthesized (top), ammonium exchanged and calcined sample (bottom).



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Fig. 8

hk0 electron diffraction patterns for conventional MCM-22 sample (top) and calcined Example 5 - left minority component with sharp closely resembling Example A - right - predominant pattern indicative of stacking disorder.

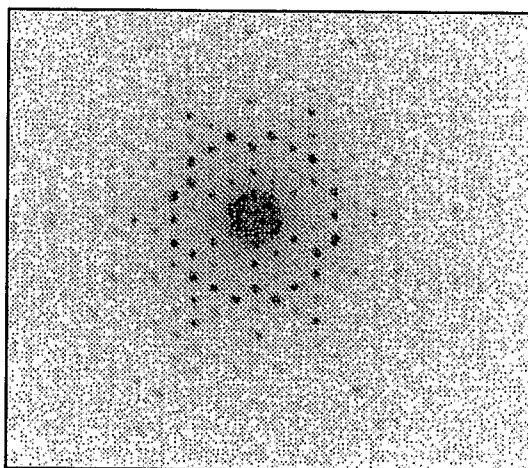


Fig. 8A

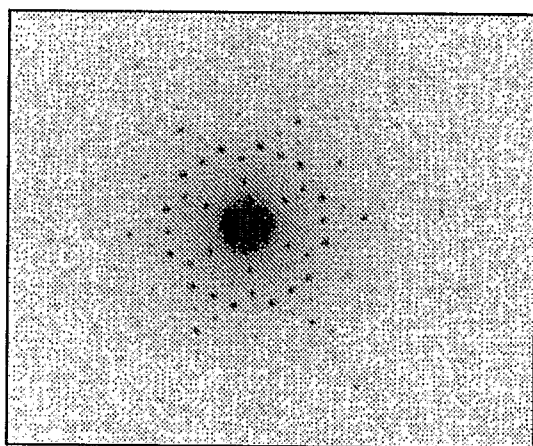


Fig. 8B

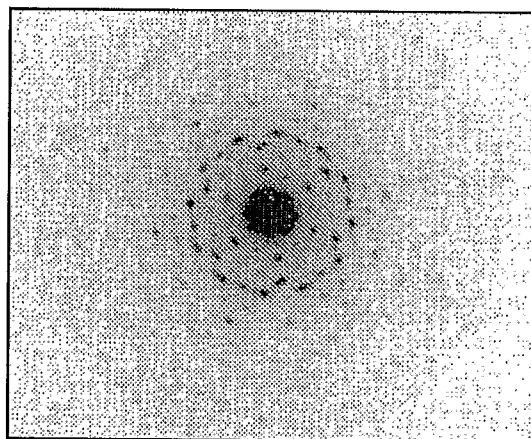


Fig. 8C

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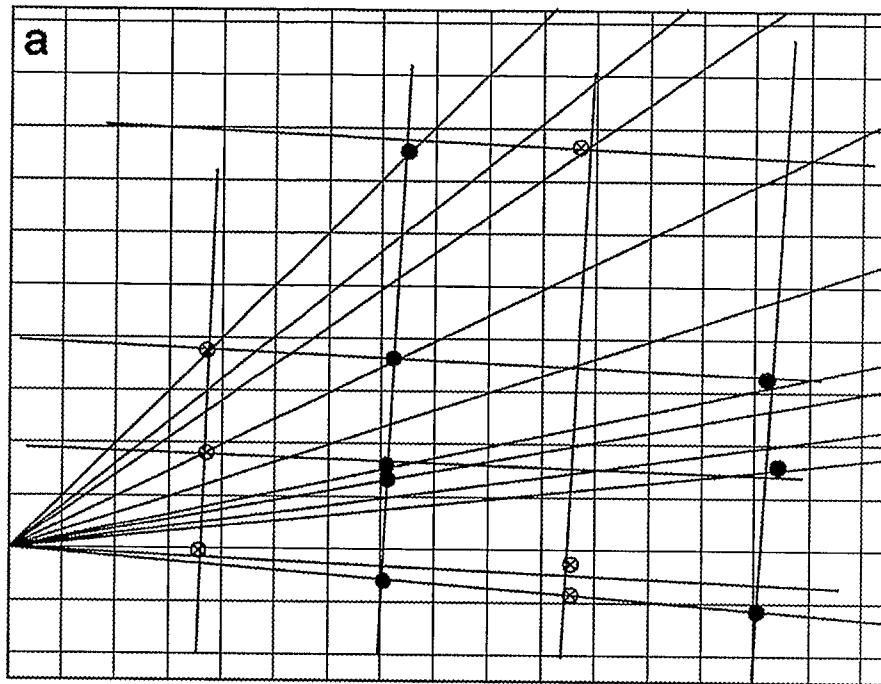


Fig. 9a

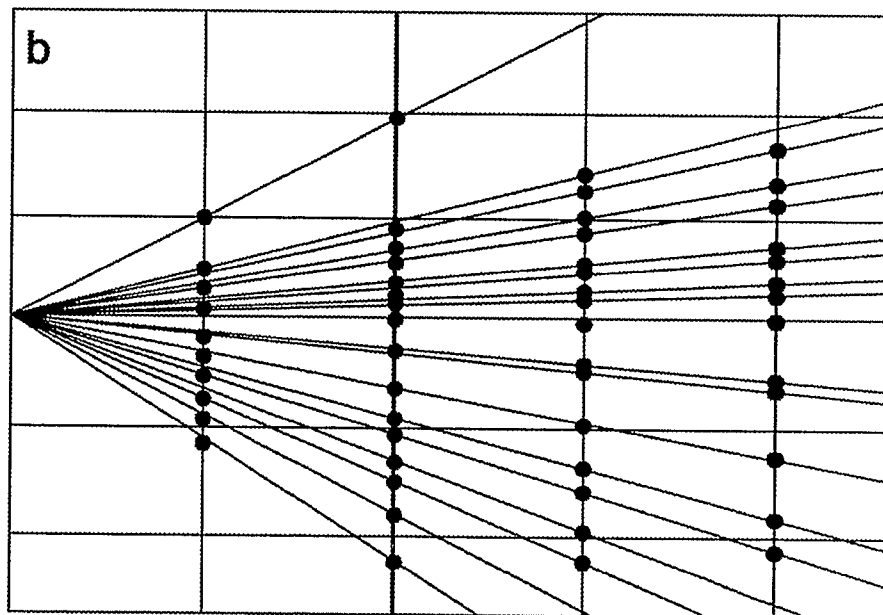


Fig. 9b

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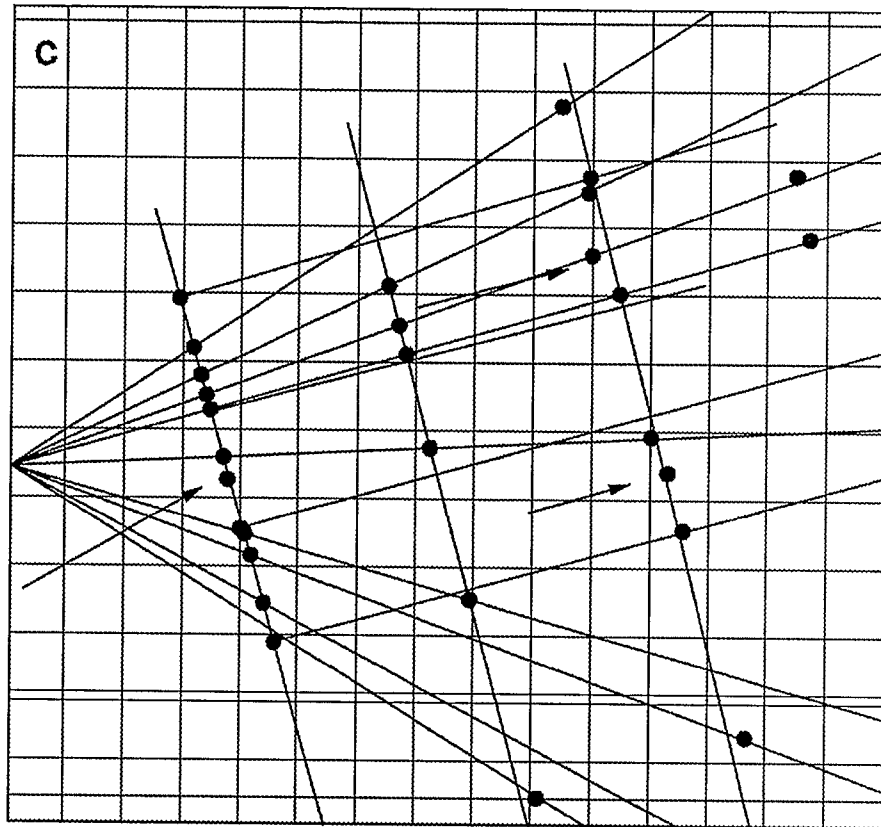


Fig. 9c